Philips Components-Signetics

Document No.	853-0148		
ECN No.	86487		
Date of Issue	November 11, 1986		
Status	Product Specification		
Memory Produ	ucts		

82S126 82S129

1K-bit TTL bipolar PROM

DESCRIPTION

The 82S126 and 82S129 are field programmable, which means that custom patterns are immediately available by following the Signetics Generic I fusing procedure. The 82S126 and 82S129 devices are supplied with all outputs at logical Low. Outputs are programmed to a logic High level at any specified address by fusing the Ni-Cr link matrix.

These devices include on-chip decoding and 2 Chip Enable inputs for ease of memory expansion. They feature either Open Collector or 3-State outputs for optimization of word expansion in bused organizations.

Ordering information can be found on the following page.

The 82S126 and 82S129 devices are also processed to military requirements for operation over the military temperature range. For specifications and ordering information, consult the Signetics Military Data Handbook.

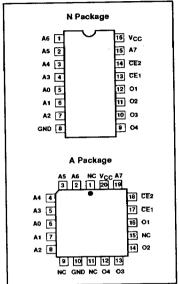
FEATURES

- Address access time: 50ns max
- Power dissipation: 0.5mW/bit typ
- Input loading: -100μA max
- On-chip address decoding
- Two Chip Enable inputs
- Output options:
 - N82S126: Open Collector
 - N82S129: 3-State
- · No separate fusing pins
- Unprogrammed outputs are Low level
- Fully TTL compatible

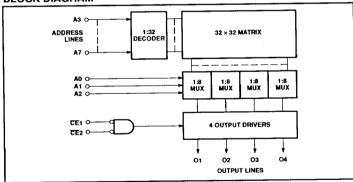
APPLICATIONS

- Prototyping/volume production
- Sequential controllers
- Format conversion
- Hardwired algorithms
- Random logic
- Code conversion

PIN CONFIGURATIONS



BLOCK DIAGRAM



1K-bit TTL bipolar PROM (256 \times 4)

82S126 / 82S129

ORDERING INFORMATION

DESCRIPTION	ORDER CODE
16-Pin Plastic Dual-In-Line 300mil-wide	N82S126 N, N82S129 N
20-Pin Plastic Leaded Chip Carrier 350mil-square	N82S126 A, N82S129 A

ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	+7.0	V _{DC}
V _{IN}	Input voltage	+5.5	V _{DC}
VoH	Output voltage High (82S126)	+5.5	V _{DC}
Vo	Output voltage Off-State (82S129)	+5.5	V _∞
T _{amb}	Operating temperature range	0 to +75	°C
T _{stg}	Storage temperature range	-65 to +150	°C

DC ELECTRICAL CHARACTERISTICS $0^{\circ}C \le T_{amb} \le +75^{\circ}C$, $4.75V \le V_{CC} \le 5.25V$

SYMBOL	PARAMETER	TEST CONDITIONS ^{1,2}	LIMITS			UNIT	
			MIN	TYP3	MAX		
input voita	ge						
V _{IL}	Low				0.8	٧	
V_{IH}	High		2.0	i		V	
V_{IC}	Clamp	$I_{IN} = -12mA$			-1.2	٧	
Output vol	tage						
	-	CE1,2 = Low					
V_{OL}	Low	I _{OUT} = 16mA			0.45	V	
V_{OH}	High (82S129)	$I_{OUT} = -2.0$ mA	2.4			V	
Input curre	ent						
I _{IL}	Low	V _{IN} = 0.45V			-100	μΑ	
l _{IH}	High	$V_{IN} = 5.5V$			40	μΑ	
Output cur	rent						
lolk	Leakage (82S126)	CE1 or CE2 = High, V _{OUT} = 5.5V			40	μΑ	
loz	Hi-Z state (82S129)	$\overline{CE}1$ or $\overline{CE}2$ = High, V_{OUT} = 5.5V			40	μA	
		$\overline{CE}1$ or $\overline{CE}2 = \text{High}$, $V_{OUT} = 0.5V$			-40	μΑ	
los	Short circuit (82S129)4	CE1,2 = Low, V _{OUT} = 0V, High stored	-15		-70	mA	
Supply cur	rent ⁵						
1cc		V _{CC} = 5.25V			120	mA	
Capacitano	æ						
		CE1 or CE2 = High, V _{CC} = 5.0V					
CIN	Input	$V_{1N} = 2.0V$		5		рF	
Cout	Output	$V_{OUT} = 2.0V$	1	8		рF	

NOTES:

- 1. Positive current is defined as into the terminal referenced.

All voltages with respect to network ground.
Typical values are at V_{CC} = 5V, T_{amb} = +25°C.
Duration of short circuit should not exceed 1 second.
Measured with all inputs grounded and all outputs open.

1K-bit TTL bipolar PROM (256 \times 4)

82S126 / 82S129

AC ELECTRICAL CHARACTERISTICS

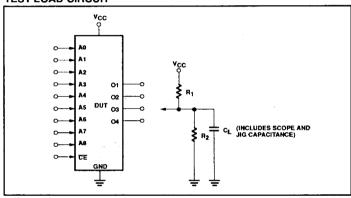
 $R_1 = 270\Omega$. $R_2 = 600\Omega$. $C_1 = 30pF$ 0°C < T_{amb} < +75°C. 4.75V < V_{CC} < 5.25V

SYMBOL	PARAMETER	то	FROM	LIMITS			UNIT
				MIN	TYP1	MAX	
Access tim	e ²		<u> </u>	•			
t _{AA}	T	Output	Address		40	50	ns
t _{CE}		Output	Chip Enable			25	ns
Disable tim	ie ³						
t _{CD}		Output	Chip Disable	Ĭ		25	ns

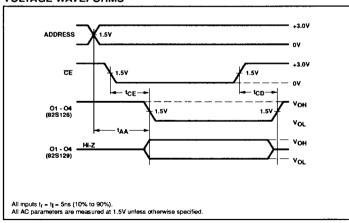
NOTES:

- Typical values are at $V_{CC} = 5V$, $T_{amb} = +25^{\circ}C$. Tested at an address cycle time of $1\mu s$.
- 3. Measured at a delta of 0.5V from Logic Level with $R_1 = 750\Omega$, $R_2 = 750\Omega$, $C_L = 5pF$.

TEST LOAD CIRCUIT



VOLTAGE WAVEFORMS



November 11, 1986